


<b>Search Notes</b> 	<b>Application/Control No.</b> 10511734	<b>Applicant(s)/Patent Under Reexamination</b> PROTIC ET AL.
	<b>Examiner</b> Lee, Shun	<b>Art Unit</b> 2884

SEARCHED			
Class	Subclass	Date	Examiner
250	370.01	6/16/2006	SL
250	370.06	6/16/2006	SL
250	370.13	6/16/2006	SL
Above	UPDATED	3/20/2007	SL

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, IBM_TDB) - See Search History Printout	3/20/2007	SL

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner